## Complete All-Region Model



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#### **Complete All-Region Model**

#### Current Equations (no simplification):

A key to the generality of the results we are about to develop is the observation that the current in the channel can be caused by both drift and diffusion:

 $I(x) = I_{drift}(x) + I_{diff}(x)$ 

- The total current in the channel must be the same for all x and equal to the drain-to-source current.
- Drift current: Using the shown figure and previous expressions:

$$I_{drift}(x) = \mu(-Q'_I) \frac{W}{\Delta x} (\psi_s(x + \Delta x) - \psi_s(x))$$

• If  $\Delta x \to 0$ 

$$I_{drift}(x) = \mu W(-Q'_I) \frac{d\psi_s(x)}{dx}$$

Diffusion current: using past expressions:

$$I_{diff}(x) = \mu W \phi_T \frac{dQ_I'}{dx}$$







#### **Current Equations**

Total current:

$$I(x) = \mu W(-Q'_I) \frac{d\psi_s(x)}{dx} + \mu W \phi_T \frac{dQ'_I}{dx}$$

• Parameters at the source end (x=0):  $\psi_{s0}$  ,  $Q_{I0}'$ 

• Integrating the equation over the L , assuming I and  $\mu$  are constant along the channel:

$$\int_{0}^{L} I_{DS} dx = \int_{\psi_{s0}}^{\psi_{sL}} \mu W(-Q_{I}') d\psi_{s}(x) + \int_{Q_{I0}'}^{Q_{IL}'} \mu W \phi_{T} dQ_{I}'$$
$$I_{DS} = \frac{W}{L} \mu \left( \int_{\psi_{s0}}^{\psi_{sL}} (-Q_{I}') d\psi_{s}(x) + \int_{Q_{I0}'}^{Q_{IL}} \phi_{T} dQ_{I}' \right)$$

$$I_{DS} = I_{DS1} + I_{DS2}$$
$$I_{DS1} = \frac{W}{L} \mu \left( \int_{\psi_{s0}}^{\psi_{sL}} (-Q_I') d\psi_s(x) \right)$$
$$I_{DS2} = \frac{W}{L} \mu \left( \int_{Q_{I0}'}^{Q_{IL}'} \phi_T dQ_I' \right)$$





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#### Current Equations ...

$$I_{DS2} = \frac{W}{L} \mu \left( \int_{Q'_{I0}}^{Q'_{IL}} \phi_T dQ'_I \right) = \frac{W}{L} \mu \phi_T (Q'_{IL} - Q'_{I0})$$

• $Q'_I$  is a function of  $\psi_s$ :

•••

$$Q_{I}' = -C_{ox}'(V_{GB} - V_{FB} - \psi_{s}) - Q_{B}'$$

$$I_{DS1} = \frac{W}{L} \mu \left( \int_{\psi_{s0}}^{\psi_{sL}} (-Q_{I}') d\psi_{s}(x) \right)$$

$$= \frac{W}{L} \mu C_{ox}' \left[ (V_{GB} - V_{FB})(\psi_{SL} - \psi_{s0}) - \frac{1}{2}(\psi_{SL}^{2} - \psi_{S0}^{2}) \right] + \frac{W}{L} \mu \left( \int_{\psi_{s0}}^{\psi_{sL}} (Q_{B}') d\psi_{s}(x) \right)$$

$$I_{DS2} = \frac{W}{L} \mu C_{ox}' \phi_{T}(\psi_{SL} - \psi_{s0}) - \frac{W}{L} \mu \phi_{T}(Q_{B}'(\psi_{SL}) - Q_{B}'(\psi_{s0}))$$



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#### Current Equations ...

But we know:

$$Q'_B = -\sqrt{2q\epsilon_s N_A}\sqrt{\psi_S} = -\gamma C'_{ox}\sqrt{\psi_S}$$

Substituting to prev. Eq.:

$$\boldsymbol{I}_{DS1} = \frac{W}{L} \mu C'_{ox} \left[ (V_{GB} - V_{FB})(\psi_{SL} - \psi_{S0}) - \frac{1}{2}(\psi_{SL}^2 - \psi_{S0}^2) - \frac{2}{3}\gamma \left(\psi_{SL}^{3/2} - \psi_{S0}^{3/2}\right) \right]$$
$$\boldsymbol{I}_{DS2} = \frac{W}{L} \mu C'_{ox} \left[ \phi_T(\psi_{SL} - \psi_{S0}) - \phi_T \gamma \left(\psi_{SL}^{1/2} - \psi_{S0}^{1/2}\right) \right]$$

Now we have the current in term of surface potential  $\psi_S$ , therefore if we can evaluate it we can find current.





By substituting  $V_{CB}$  to  $V_{SB}$  and  $V_{DB}$  for each end of channel we have:

$$\psi_{S0} = V_{GB} - V_{FB} - \gamma \sqrt{\psi_{S0} + e^{-(2\phi_F + V_{SB})/\phi_T}(\phi_T e^{\psi_{S0}/\phi_T})}$$
$$\psi_{SL} = V_{GB} - V_{FB} - \gamma \sqrt{\psi_{SL} + e^{-(2\phi_F + V_{DB})/\phi_T}(\phi_T e^{\psi_{SL}/\phi_T})}$$

These equations can be solved for  $\psi_{S0}$  and  $\psi_{SL}$  by iteration. This can easily be done with a computer.

•Two techniques have emerged as the preferred approaches to compute  $\psi_S$  .

• First- or second-order Newton-Raphson scheme : uses an iterative numerical procedure, in which a good initial estimate is made of  $\psi_S$ . Convergence to tight tolerances can be achieved in two to three iterations.





•A plot of  $\psi_{SL}/\psi_{S0}$  vs.  $V_{DB}/V_{SB}$  is shown •The plot saturates at a value dependent on  $V_{GB}$ , shown in Fig. Edge effect near drain and source are neglected here. (small dimension effect). Now to plot <u>fig.</u> we raise the V<sub>DB</sub> voltage (as a parameter) respect to V<sub>SB</sub> (keep it fix). • $\psi_{SL}$  and  $\psi_{S0}$  can be calculated from previous equations respect to  $V_{DB}$  and  $V_{SB}$ . Now with <u>current equations</u> we can find  $I_{DS1}$  and  $I_{DS2}$ . Finally  $I_{DS} = I_{DS1} + I_{DS2}$ <u>Note</u>: described equations predicts the current in all these regions. Experiments agree well with this



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expression

- Saturation always take place for large V<sub>DB</sub>.
- •For following figure saturation effect is shown for specific  $V_{GB}(=V_{GB4})$ .
- Drain end of the channel:
  - Increasing  $V_{DB}$  eventually drives the drain end of the channel into weak inversion and then depletion, where  $\psi_{SL}$  becomes practically constant at a value that depends only on  $V_{GB}(=V_{GB4})$ .
  - Increasing  $V_{DB}$  further has little effect on  $\psi_{SL}$  and  $|Q'_I|$  becomes very small. Thus  $I_{DS1}$  and  $I_{DS2}$  also become independent of  $V_{DB}$ .

Source end of the channel:

- As the  $V_{SB}$  is constant and it selected so that the this part be at strong inversion therefore it is heavily inverted due to very large  $|Q'_I|$ .
- $\psi_{S0}$  is strongly dependent to  $V_{SB}$ .
- The current at any point in the channel should be constant and it is not dependent only to  $|Q'_I|$  as shown in <u>previous equations</u>. (drift and <u>diffusion</u>)



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- In this figure consider that V<sub>DB</sub> selected so that I<sub>DS</sub> is in saturation region.
- By changing the V<sub>GB</sub>, I<sub>DS</sub> components I<sub>DS1</sub> and I<sub>DS2</sub> can be calculated.
- To include a large range of currents, a logarithmic vertical axis is used.
- Here V<sub>DB</sub> > V<sub>SB</sub>, so that the more heavily inverted channel end is the one next to the source.
- Everything below moderate inversion is called weak inversion.
- It is seen in Fig. that:
  - In <u>strong</u> inversion, I<sub>DS</sub> ≈ I<sub>DS1</sub>, so the current is mainly due to the presence of drift.
  - In <u>weak</u> inversion , I<sub>DS</sub> ≈ I<sub>DS2</sub>, so the current is mainly due to the presence of diffusion.
  - In <u>moderate</u> inversion both *I<sub>DS1</sub>* and *I<sub>DS2</sub>* are important.



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- In following Fig., we show a comparison of the preceding model (lines) to full computer solution of the semiconductor equations (dots).
- The simulation is a 2D numerical solution of the Poisson and drift-diffusion equations, allowing for the spreading of the inversion layer below the surface. The values of W and L used were on purpose chosen very large, to minimize edge effects.





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#### A Graphical Interpretation

In this figure, we show  $-Q'_I$  vs.  $\psi_S$ , as obtained from below Eq., for a given  $V_{GB}$ .

$$Q_I' = -C_{ox}' (V_{GB} - V_{FB} - \psi_s - \gamma \sqrt{\psi_s})$$

- The only part of this curve that is relevant to us is that between  $\psi_{S0}$  and  $\psi_{SL}$  the values of the surface potential at the source and the drain.
- This curve should also satisfy following Eq. (derived for 3 terminal device  $C'_{0x}(V_{GB} V_{FB})$  before):

$$Q_I' = -\sqrt{2q\epsilon_s N_A} \left( \sqrt{\psi_s + \phi_T e^{(\psi_s - (2\phi_F + \mathbf{V_{CB}}))/\phi_T}} - \sqrt{\psi_s} \right)$$

- $Q'_{I0}$  and  $Q'_{IL}$  corresponds to surface potential  $\psi_{S0}$  and  $\psi_{SL}$ .
- Shaded region is regarding to following integral:

$$I_{DS1} = \frac{W}{L} \mu \left( \int_{\psi_{s0}}^{\psi_{sL}} (-Q_I') d\psi_S(x) \right)$$

Iet us determine the point where the curve representing above Eq intersects the horizontal axis.



This can be found by setting that equation equal to zero and solving for  $\psi_S$ ,. The result is nothing but  $\psi_{Sa}$ . (first introduced in 2 terminal device)

 $\psi_{Sa}$  is the potential which inversion layer is negligible.



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#### A Graphical Interpretation...

- •The graphical construction in previous Fig. facilitates a feel for the behavior of **I**<sub>DS1</sub> and **I**<sub>DS2</sub>.
- •The particular operating point assumed in previous Fig. happens to be in the strong inversion nonsaturation region. Why ?
  - When  $V_{DB}$  is raised a little, the corresponding  $-Q'_I$ ; curve will move to the right in the figure; the value of  $\psi_{SL}$  will increase, and so will the currents in Eq. thus  $I_{DS} = I_{DS1} + I_{DS2}$  is increase.
- Eventually, as  $V_{DB}$  is raised further, the corresponding  $Q'_I$ ; plot will move far to the right, as illustrated by the broken-line curve;  $\psi_{SL}$  will asymptotically reach the value  $\psi_{Sa}$  and will be unable to rise further.
- $Q_{IL}'$  now becomes essentially zero, and the trapezoid becomes a triangle;  $I_{DS1}$  and  $I_{DS2}$  stay fixed as  $V_{DB}$  is raised further.
- •We have now reached **saturation**, and the current flattens out at its maximum value.



#### Symmetry

It is clear from previous Eqs. that **I**<sub>DS</sub> can be written in the form:

$$I_{DS} = \frac{W}{L} (f(\psi_{SL}) - f(\psi_{S0}))$$
$$f(\psi_S) = \mu C'_{ox} \left[ (V_{GB} - V_{FB} + \phi_T)\psi_S + \phi_T \gamma \psi_S^{1/2} - \frac{1}{2}\psi_S^2 - \frac{2}{3}\gamma \psi_S^{3/2} \right]$$

•This Eqs. is in a form that emphasizes the symmetry of the transistor.

If the potentials at the source and drain are interchanged, the only difference will be that I<sub>DS</sub> will change sign.



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# Surface Potential, Charge, and Currents vs. Position

For visualizing transistor operation and for calculating certain quantities, it will be useful to relate the surface potential  $\psi_S$  to the position along the channel x.

$$I_{DS} = \frac{W}{L} F(\psi_{SL}, \psi_{S0})$$

where F is an appropriate function.

•Furthermore as the current is independent of *x* therefore:

$$I_{DS} = \frac{W}{x} F(\psi_S(x), \psi_{S0})$$

Eliminating  $I_{DS}$  between the preceding two equations we obtain:  $x = F(\psi_S(x), \psi_{S0})$ 

$$\frac{1}{L} = \frac{F(\psi_{SL}, \psi_{S0})}{F(\psi_{SL}, \psi_{S0})}$$

This equation gives the relation between x and  $\psi_S(x)$ .





#### Surface Potential, Charge, ...

The easy way to get results from it is to give values  $\psi_S(x)$  between  $\psi_{S0}$  and  $\psi_{SL}$  and determine x. The results is shown in following figure.

Regions of inversions:

- In moderate inversion, the variation of ψ<sub>S</sub> with x for V<sub>DB</sub> > V<sub>SB</sub> is less pronounced.
- In weak inversion, the two curves would practically coincide because, in that region, the variations of the surface potential along the channel is negligible even when V<sub>DB</sub> > V<sub>SB</sub>.

•  $|Q'_I|$  as <u>predicted</u> by the all-region model decreases monotonically along the channel as we go from the source toward the drain, although we can see it here as well. As the potential increase...

•One can similarly evaluate  $\frac{d\psi_s(x)}{dx}$  and  $\frac{dQ'_I}{dx}$  as a function of x.

It is then found that  $I_{drift}(x)$  decreases with x, whereas  $I_{diff}(x)$  increases.



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 $\psi_{\mathbf{x}}(\mathbf{x})$